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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

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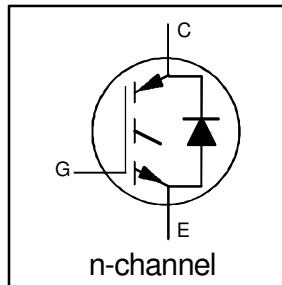
Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China

INSULATED GATE BIPOLAR TRANSISTOR
 WITH ULTRAFAST SOFT RECOVERY DIODE

UltraFast CoPack IGBT

Features

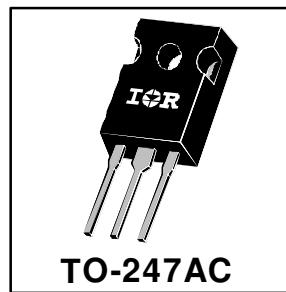
- Switching-loss rating includes all "tail" losses
- HEXFRED™ soft ultrafast diodes
- Optimized for high operating frequency (over 5kHz)
 See Fig. 1 for Current vs. Frequency curve



$V_{CES} = 600V$
$V_{CE(sat)} \leq 3.0V$
@ $V_{GE} = 15V, I_C = 20A$

Description

Co-packaged IGBTs are a natural extension of International Rectifier's well known IGBT line. They provide the convenience of an IGBT and an ultrafast recovery diode in one package, resulting in substantial benefits to a host of high-voltage, high-current, motor control, UPS and power supply applications.



Absolute Maximum Ratings

	Parameter	Max.	Units
V_{CES}	Collector-to-Emitter Voltage	600	V
$I_C @ T_C = 25^\circ C$	Continuous Collector Current	40	
$I_C @ T_C = 100^\circ C$	Continuous Collector Current	20	
I_{CM}	Pulsed Collector Current ①	160	A
I_{LM}	Clamped Inductive Load Current ②	160	
$I_F @ T_C = 100^\circ C$	Diode Continuous Forward Current	15	
I_{FM}	Diode Maximum Forward Current	160	
V_{GE}	Gate-to-Emitter Voltage	± 20	V
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	160	W
$P_D @ T_C = 100^\circ C$	Maximum Power Dissipation	65	
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ C$
	Soldering Temperature, for 10 sec.	300 (0.063 in. (1.6mm) from case)	
	Mounting Torque, 6-32 or M3 Screw.	10 lbf-in (1.1 N·m)	

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
R_{eJC}	Junction-to-Case - IGBT	—	—	0.77	
R_{eJC}	Junction-to-Case - Diode	—	—	1.7	$^\circ C/W$
R_{eCS}	Case-to-Sink, flat, greased surface	—	0.24	—	
R_{eJA}	Junction-to-Ambient, typical socket mount	—	—	40	
Wt	Weight	—	6 (0.21)	—	g (oz)

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Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{CES}}$	Collector-to-Emitter Breakdown Voltage ③	600	—	—	V	$V_{\text{GE}} = 0\text{V}, I_C = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{CES}/\Delta T_J}$	Temp. Coeff. of Breakdown Voltage	—	0.63	—	V/°C	$V_{\text{GE}} = 0\text{V}, I_C = 1.0\text{mA}$
$V_{\text{CE}(\text{on})}$	Collector-to-Emitter Saturation Voltage	—	2.2	3.0	V	$I_C = 20\text{A}$ $V_{\text{GE}} = 15\text{V}$
		—	2.7	—		$I_C = 40\text{A}$ See Fig. 2, 5
		—	2.3	—		$I_C = 20\text{A}, T_J = 150^\circ\text{C}$
$V_{\text{GE}(\text{th})}$	Gate Threshold Voltage	3.0	—	5.5		$V_{\text{CE}} = V_{\text{GE}}, I_C = 250\mu\text{A}$
$\Delta V_{\text{GE}(\text{th})/\Delta T_J}$	Temp. Coeff. of Threshold Voltage	—	-13	—	mV/°C	$V_{\text{CE}} = V_{\text{GE}}, I_C = 250\mu\text{A}$
g_{fe}	Forward Transconductance ④	11	18	—	S	$V_{\text{CE}} = 100\text{V}, I_C = 20\text{A}$
I_{CES}	Zero Gate Voltage Collector Current	—	—	250	μA	$V_{\text{GE}} = 0\text{V}, V_{\text{CE}} = 600\text{V}$
		—	—	3500		$V_{\text{GE}} = 0\text{V}, V_{\text{CE}} = 600\text{V}, T_J = 150^\circ\text{C}$
V_{FM}	Diode Forward Voltage Drop	—	1.3	1.7	V	$I_C = 15\text{A}$ See Fig. 13
		—	1.2	1.6		$I_C = 15\text{A}, T_J = 150^\circ\text{C}$
I_{GES}	Gate-to-Emitter Leakage Current	—	—	±100	nA	$V_{\text{GE}} = \pm 20\text{V}$

Switching Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
Q_g	Total Gate Charge (turn-on)	—	51	67	nC	$I_C = 20\text{A}$
Q_{ge}	Gate - Emitter Charge (turn-on)	—	8.9	11		$V_{\text{CC}} = 400\text{V}$
Q_{gc}	Gate - Collector Charge (turn-on)	—	20	33		See Fig. 8
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	63	—	ns	$T_J = 25^\circ\text{C}$
t_r	Rise Time	—	54	—		$I_C = 20\text{A}, V_{\text{CC}} = 480\text{V}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	160	240		$V_{\text{GE}} = 15\text{V}, R_G = 10\Omega$
t_f	Fall Time	—	120	200		Energy losses include "tail" and diode reverse recovery. See Fig. 9, 10, 11, 18
E_{on}	Turn-On Switching Loss	—	0.65	—	mJ	
E_{off}	Turn-Off Switching Loss	—	1.25	—		
E_{ts}	Total Switching Loss	—	1.90	3.0		
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	65	—	ns	$T_J = 150^\circ\text{C}$, See Fig. 9, 10, 11, 18
t_r	Rise Time	—	53	—		$I_C = 20\text{A}, V_{\text{CC}} = 480\text{V}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	280	—		$V_{\text{GE}} = 15\text{V}, R_G = 10\Omega$
t_f	Fall Time	—	210	—		Energy losses include "tail" and diode reverse recovery. See Fig. 9, 10, 11, 18
E_{ts}	Total Switching Loss	—	3.0	—	mJ	
L_E	Internal Emitter Inductance	—	13	—		Measured 5mm from package
C_{ies}	Input Capacitance	—	1500	—		
C_{oes}	Output Capacitance	—	190	—	pF	$V_{\text{GE}} = 0\text{V}$
C_{res}	Reverse Transfer Capacitance	—	17	—		$V_{\text{CC}} = 30\text{V}$ See Fig. 7
$f = 1.0\text{MHz}$						
t_{rr}	Diode Reverse Recovery Time	—	42	60	ns	$T_J = 25^\circ\text{C}$ See Fig.
		—	74	120		$T_J = 125^\circ\text{C}$ 14
I_{rr}	Diode Peak Reverse Recovery Current	—	4.0	6.0	A	$T_J = 25^\circ\text{C}$ See Fig.
		—	6.5	10		$T_J = 125^\circ\text{C}$ 15
Q_{rr}	Diode Reverse Recovery Charge	—	80	180	nC	$T_J = 25^\circ\text{C}$ See Fig.
		—	220	600		$T_J = 125^\circ\text{C}$ 16
$dI_{(\text{rec})M}/dt$	Diode Peak Rate of Fall of Recovery During t_b	—	188	—	A/μs	$T_J = 25^\circ\text{C}$ See Fig.
		—	160	—		$T_J = 125^\circ\text{C}$ 17

Notes:

① Repetitive rating; $V_{\text{GE}}=20\text{V}$, pulse width limited by max. junction temperature.
(See fig. 20)

② $V_{\text{CC}}=80\%(V_{\text{CES}})$, $V_{\text{GE}}=20\text{V}$, $L=10\mu\text{H}$, $R_G=10\Omega$, (See fig. 19)

③ Pulse width $\leq 80\mu\text{s}$; duty factor $\leq 0.1\%$.

④ Pulse width $5.0\mu\text{s}$, single shot.

$I_F = 15\text{A}$
 $V_R = 200\text{V}$
 $di/dt = 200\text{A}/\mu\text{s}$

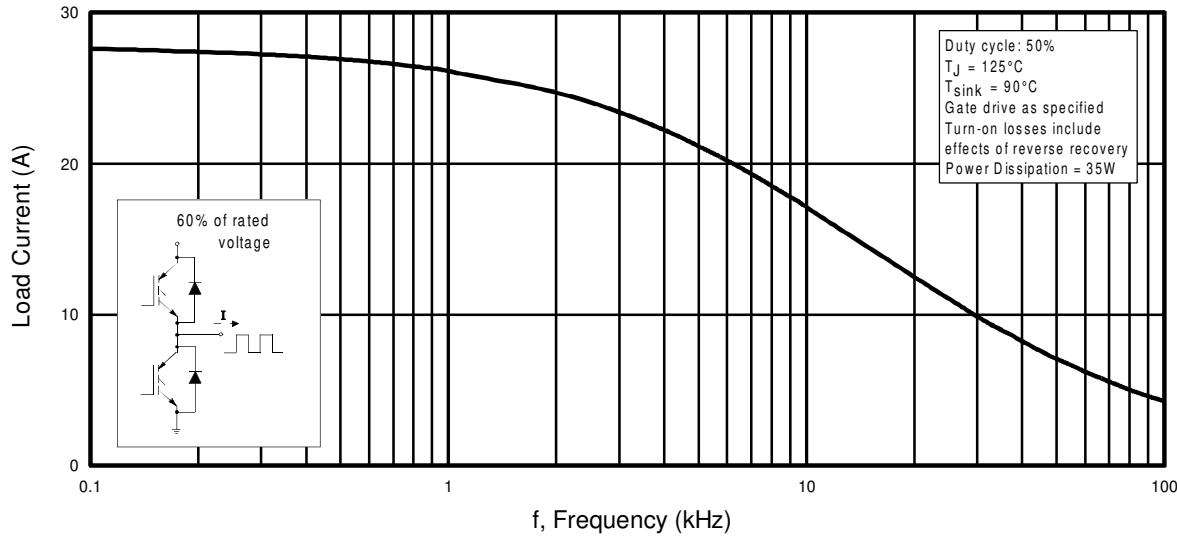


Fig. 1 - Typical Load Current vs. Frequency
(Load Current = I_{RMS} of fundamental)

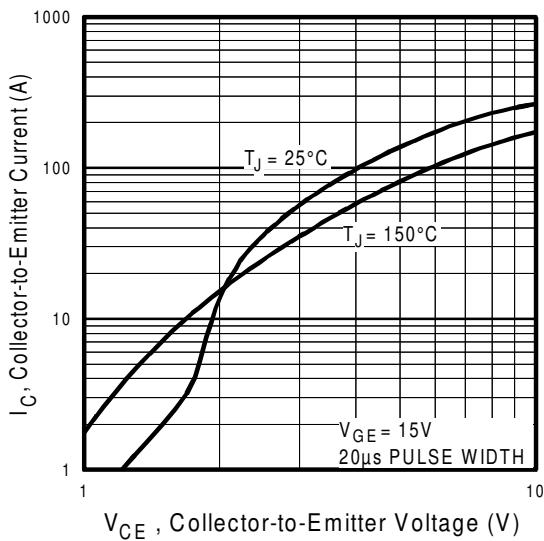


Fig. 2 - Typical Output Characteristics

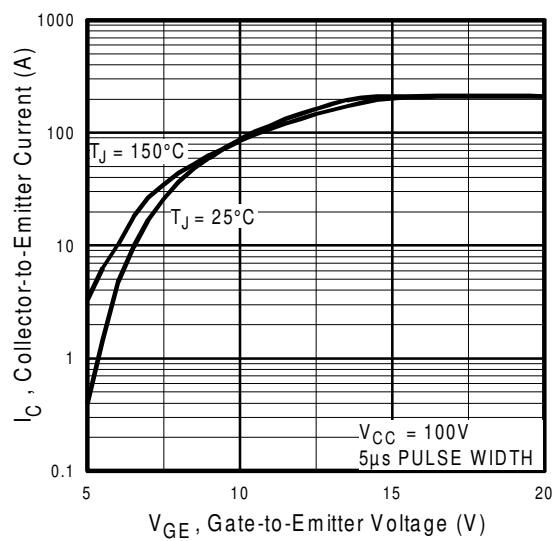


Fig. 3 - Typical Transfer Characteristics

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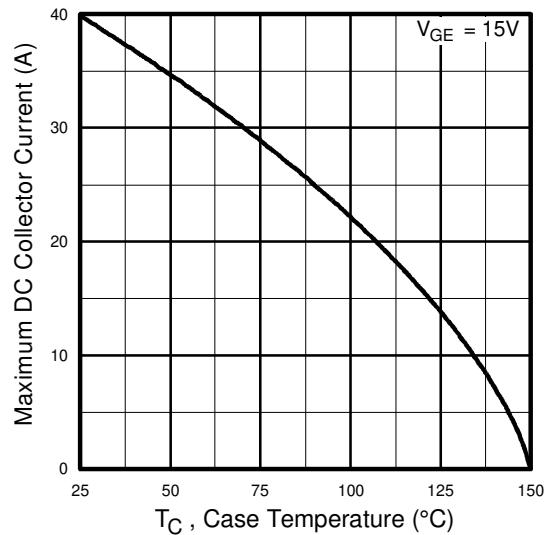


Fig. 4 - Maximum Collector Current vs.
Case Temperature

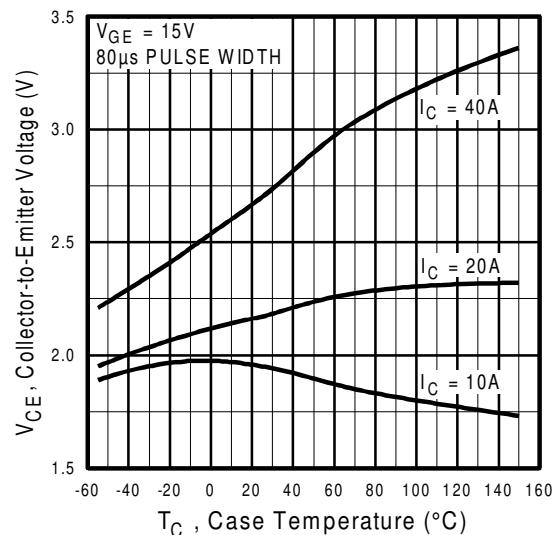


Fig. 5 - Collector-to-Emitter Voltage vs.
Case Temperature

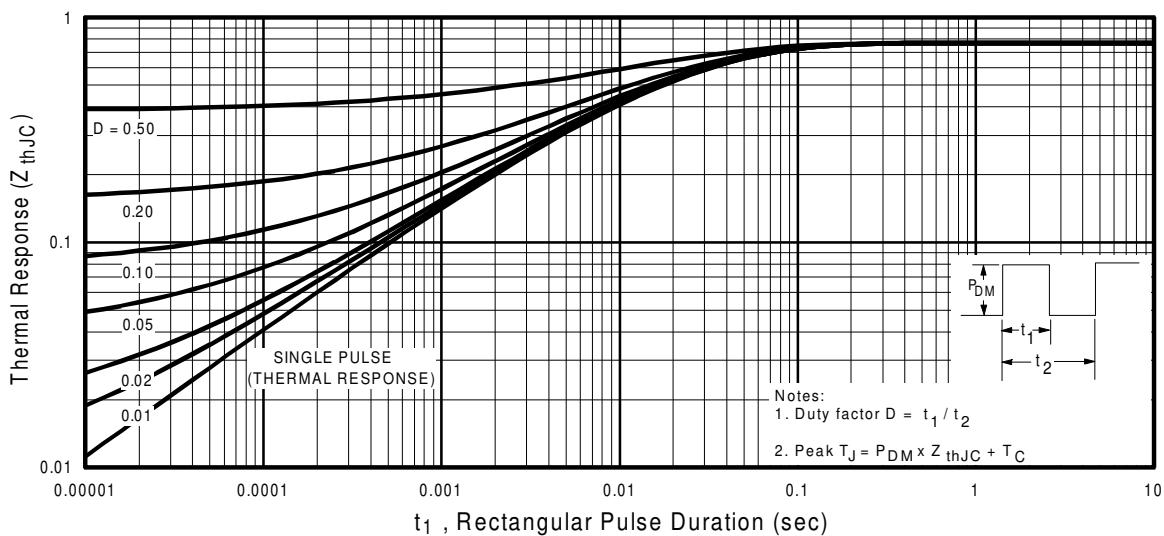
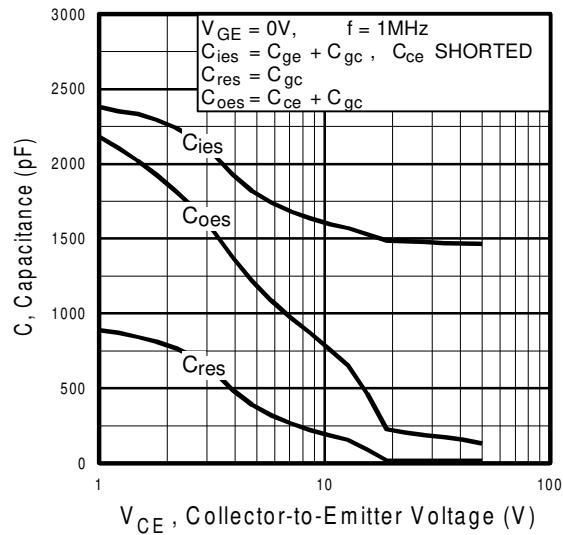
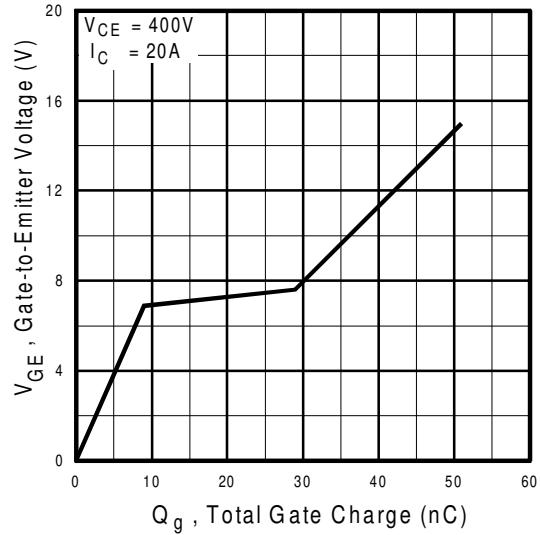


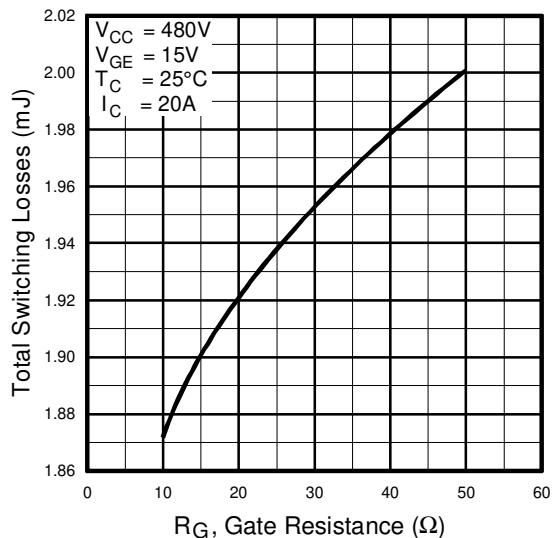
Fig. 6 - Maximum IGBT Effective Transient Thermal Impedance, Junction-to-Case



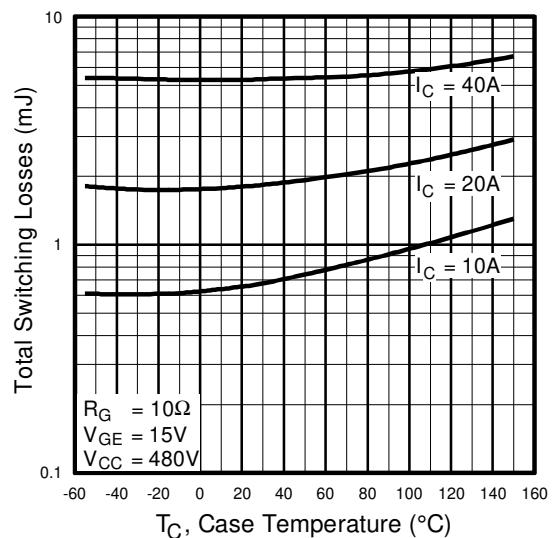
**Fig. 7 - Typical Capacitance vs.
Collector-to-Emitter Voltage**



**Fig. 8 - Typical Gate Charge vs.
Gate-to-Emitter Voltage**



**Fig. 9 - Typical Switching Losses vs. Gate
Resistance**



**Fig. 10 - Typical Switching Losses vs.
Case Temperature**

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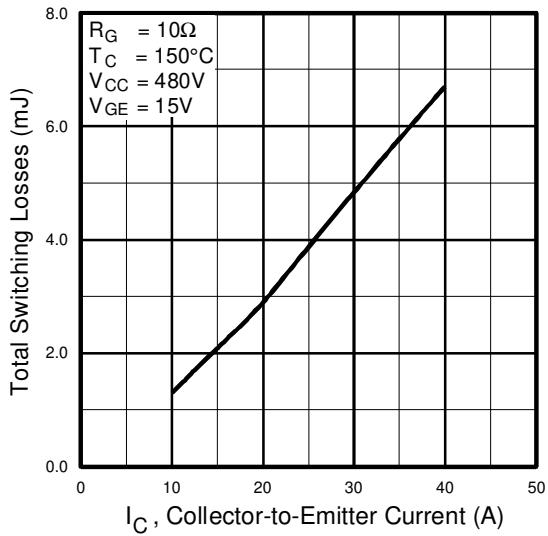


Fig. 11 - Typical Switching Losses vs.
Collector-to-Emitter Current

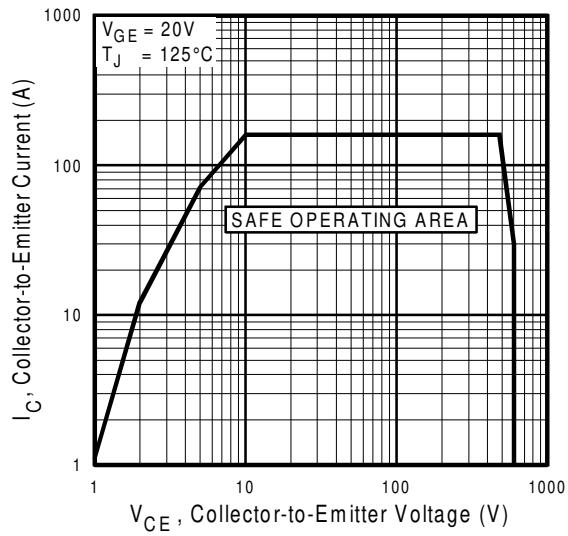


Fig. 12 - Turn-Off SOA

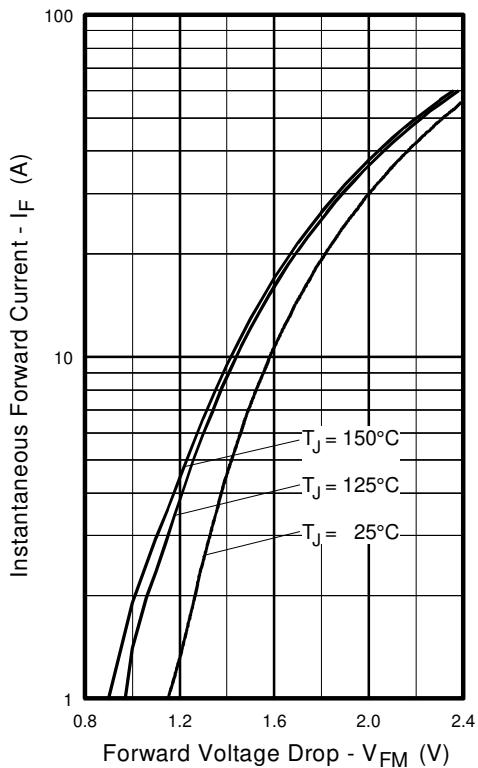


Fig. 13 - Maximum Forward Voltage Drop vs. Instantaneous Forward Current

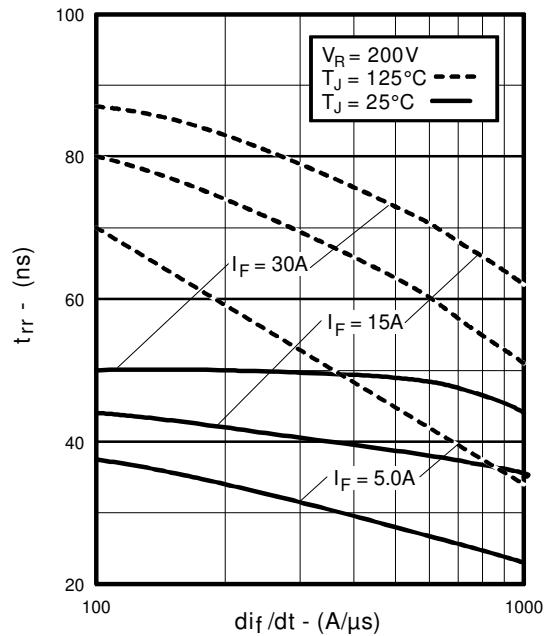


Fig. 14 - Typical Reverse Recovery vs. di_f/dt

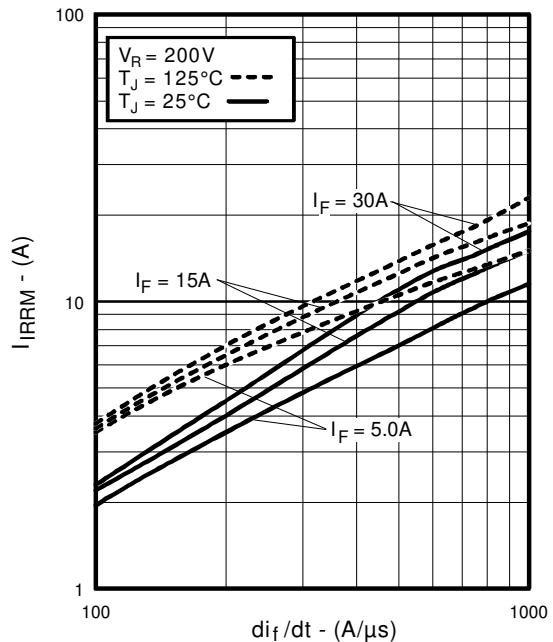


Fig. 15 - Typical Recovery Current vs. di_f/dt

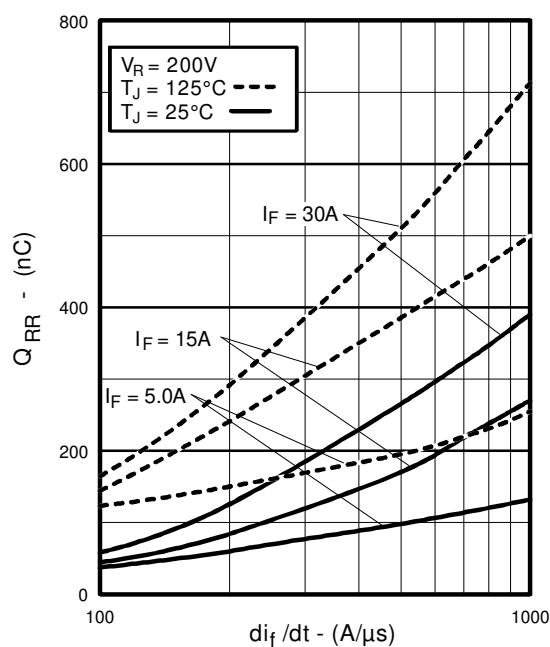


Fig. 16 - Typical Stored Charge vs. di_f/dt

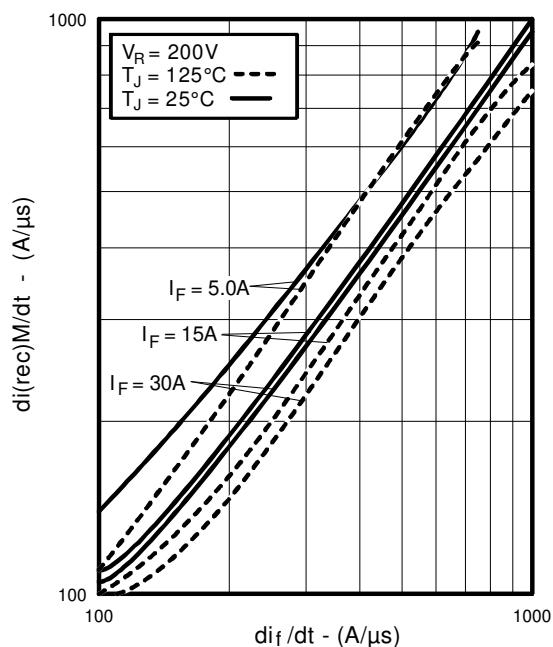


Fig. 17 - Typical $d(i_{rec})/dt$ vs. di_f/dt

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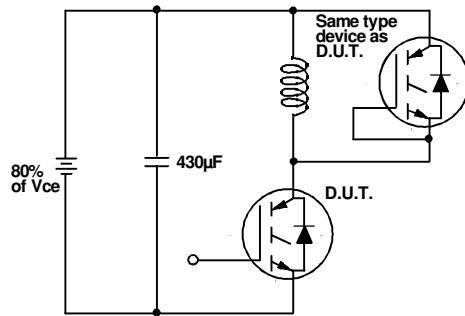


Fig. 18a - Test Circuit for Measurement of I_{LM} , E_{on} , $E_{off(diode)}$, t_{rr} , Q_{rr} , I_{rr} , $t_{d(on)}$, t_r , $t_{d(off)}$, t_f

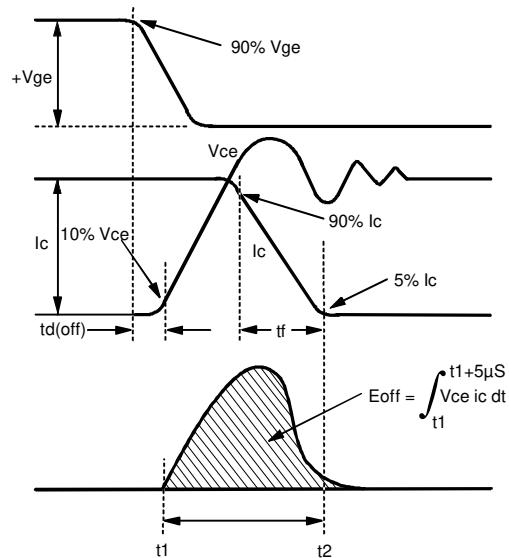


Fig. 18b - Test Waveforms for Circuit of Fig. 18a, Defining E_{off} , $t_{d(off)}$, t_f

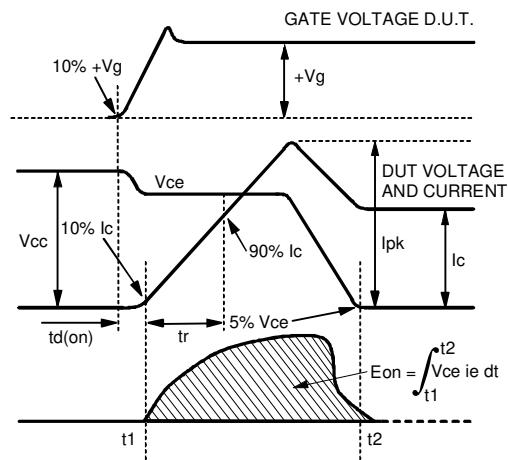


Fig. 18c - Test Waveforms for Circuit of Fig. 18a, Defining E_{on} , $t_{d(on)}$, t_r

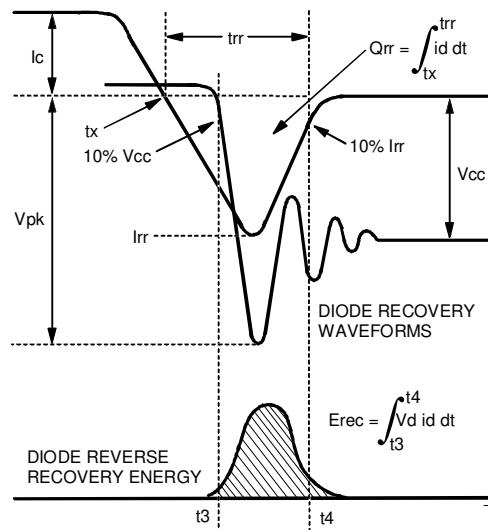


Fig. 18d - Test Waveforms for Circuit of Fig. 18a, Defining E_{rec} , t_{rr} , Q_{rr} , I_{rr}

Refer to Section D for the following:
Appendix D: Section D - page D-6

- Fig. 18e - Macro Waveforms for Test Circuit of Fig. 18a
- Fig. 19 - Clamped Inductive Load Test Circuit
- Fig. 20 - Pulsed Collector Current Test Circuit

Note: For the most current drawings please refer to the IR website at:
<http://www.irf.com/package/>